Search Notes				

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/578,317	SHINADA ET AL.	
Examiner	Art Unit	
Noah Kamen	3747	

	SEAR	CHED	
Class	Subclass	Date	Examiner
123	184.53	12/10/2007	/NK/
	184.57		
181	204		
	229		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	12/10/2007	/NK/
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